

TMA4275 LIFETIME ANALYSIS

Slides 6: Nelson-Aalen estimator and TTT plot

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WHY IS AN ESTIMATE OF $Z(t)$ USEFUL?

Note first that $Z'(t) = z(t)$. Thus,

- T is IFR $\Leftrightarrow z(t)$ is *increasing* $\Leftrightarrow Z(t)$ is *convex*
- T is DFR $\Leftrightarrow z(t)$ is *decreasing* $\Leftrightarrow Z(t)$ is *concave*

Thus a plot of an estimate $\hat{Z}(t)$ can give us information on whether the distribution of T is IFR (*increasing failure rate*) or DFR (*decreasing failure rate*).

ESTIMATING $Z(t)$ BY THE KM-ESTIMATOR

Recall that $R(t) = e^{-Z(t)}$, so

$$Z(t) = -\ln R(t)$$

Thus - if $\hat{R}_{KM}(t)$ is the KM-estimator for $R(t)$, then we can define,

$$\begin{aligned}\hat{Z}_{KM}(t) &= -\ln \hat{R}_{KM}(t) \\ &= -\ln \prod_{T_{(i)} \leq t} \frac{n_i - d_i}{n_i} \\ &= -\sum_{T_{(i)} \leq t} \ln \left(1 - \frac{d_i}{n_i}\right) \\ &\approx \sum_{T_{(i)} \leq t} \frac{d_i}{n_i}\end{aligned}$$

where we used that for small x is

$$-\ln(1 - x) \approx x$$

The Nelson-Aalen estimator (NA-estimator) is simply defined by

$$\hat{Z}_{NA}(t) = \sum_{T_{(i)} \leq t} \frac{d_i}{n_i}$$

It can then be shown that its variance can be estimated by

$$\widehat{\text{Var}}(\hat{Z}_{NA}(t)) = \sum_{T_{(i)} \leq t} \frac{d_i}{n_i^2}$$

Note: The Nelson-Aalen estimator is *not* included in MINITAB (only “hazard plot” which is in fact not a correct). For this course has been made a *MINITAB Macro* (see MINITAB Macros on the Software webpage).

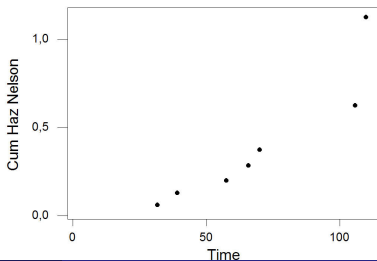
In the following we shall have a closer look at how the Nelson-Aalen estimator can be motivated from properties of the exponential distribution.

EXAMPLE: NELSON-AALEN ESTIMATOR

Row	C1	C2
1	31,7	1
2	39,2	1
3	57,5	1
4	65,0	0
5	65,8	1
6	70,0	1
7	75,0	0
8	75,2	0
9	87,5	0
10	88,3	0
11	94,2	0
12	101,7	0
13	105,8	1
14	109,2	0
15	110,0	1
16	130,0	0

Row	Time	Numb at risk	1/Numb at risk	Cum Haz Nelson	Survival Nelson
1	31,7	16	0,062500	0,06250	0,939413
2	39,2	15	0,066667	0,12917	0,878827
3	57,5	14	0,071429	0,20060	0,818244
4	65,8	12	0,083333	0,28393	0,752820
5	70,0	11	0,090909	0,37484	0,687401
6	105,8	4	0,250000	0,62484	0,535348
7	110,0	2	0,500000	1,12484	0,324705

Nelson Plot



Suppose an item with lifetime T is still alive at time s . The probability of surviving an additional t time is then

$$\begin{aligned}R(t | s) &\equiv P(T > s + t | T > s) \\ &= \frac{P(T > s + t \cap T > s)}{P(T > s)} \\ &= \frac{R(s + t)}{R(s)}\end{aligned}$$

This is called the *conditional survival function* of the item at time t , or *the distribution of the residual life*. The following is its expectation, called *Mean Residual Life*:

$$\begin{aligned}MRL(t) &= \int_0^{\infty} R(t | s) dt = \int_0^{\infty} \frac{R(s + t)}{R(s)} dt \\ &= \frac{1}{R(s)} \int_s^{\infty} R(t) dt\end{aligned}$$

PROPERTIES OF THE EXPONENTIAL DISTRIBUTION:

1. The memoryless property

Write $T \sim \text{expon}(\lambda)$ if $f(t) = \lambda e^{-\lambda t}$; $R(t) = P(T > t) = e^{-\lambda t}$, $t > 0$.

For $T \sim \text{expon}(\lambda)$ we therefore have

$$R(t | s) = P(T > s + t | T > s) = \frac{R(s + t)}{R(s)} = \frac{e^{-\lambda(s+t)}}{e^{-\lambda s}} = e^{-\lambda t} = R(t).$$

This is called *the memoryless property* of the exponential distribution.

For any age s , the remaining life has same distribution as for a new item.

2. Let $T \sim \text{expon}(\lambda)$ and let $W = aT$. Then $W \sim \text{expon}(\lambda/a)$.

Proof:

$$P(W > w) = P(aT > w) = P\left(T > \frac{w}{a}\right) = e^{-\left(\frac{\lambda}{a}\right)w}$$

3. Let T_i for $i = 1, \dots, n$ be independent, with $T_i \sim \text{expon}(\lambda_i)$. Let $W = \min(T_1, \dots, T_n)$. Then $W \sim \text{expon}(\sum_{i=1}^n \lambda_i)$.

Proof:

$$\begin{aligned} P(W > w) &= P(\min(T_1, \dots, T_n) > w) \\ &= P(T_1 > w, T_2 > w, \dots, T_n > w) \\ &= P(T_1 > w)P(T_2 > w) \cdots P(T_n > w) \\ &= e^{-(\lambda_1 + \dots + \lambda_n)w}, \end{aligned}$$

so $W \sim \text{expon}(\lambda_1 + \dots + \lambda_n)$

4. In particular if T_1, \dots, T_n are independent each with distribution $\text{expon}(\lambda)$, then

$$W = \min(T_1, \dots, T_n) \sim \text{expon}(n\lambda)$$

So a series system of n components with lifetimes that are independent and exponentially distributed with hazard rate λ , has a lifetime which is exponential with hazard rate $n\lambda$ and hence

$$\text{MTTF} = \frac{1}{n\lambda} = \frac{\text{Component MTTF}}{n}$$

5. Let T_1, \dots, T_n be independent each with distribution $\text{expon}(\lambda)$. Let the ordering of these be

$$T_{(1)} < T_{(2)} < \dots < T_{(n)}$$

Then

$$\begin{aligned} & nT_{(1)} \\ & (n-1)(T_{(2)} - T_{(1)}) \\ & (n-2)(T_{(3)} - T_{(2)}) \\ & \vdots \\ & (n-i+1)(T_{(i)} - T_{(i-1)}) \\ & \vdots \\ & (T_{(n)} - T_{(n-1)}) \end{aligned}$$

are independent and identically distributed as $\text{expon}(\lambda)$.

- 5b. Let T_1, \dots, T_n be independent each with distribution $\text{expon}(\lambda)$. Let the ordering of these be

$$T_{(1)} < T_{(2)} < \dots < T_{(n)}$$

Then

$$\begin{aligned} T_{(1)} &\sim \text{expon}(n\lambda) \\ T_{(2)} - T_{(1)} &\sim \text{expon}((n-1)\lambda) \\ T_{(3)} - T_{(2)} &\sim \text{expon}((n-2)\lambda) \\ &\vdots \\ T_{(i)} - T_{(i-1)} &\sim \text{expon}((n-i+1)\lambda) \\ &\vdots \\ T_{(n)} - T_{(n-1)} &\sim \text{expon}(\lambda) \end{aligned}$$

are independent with the displayed exponential distributions.

To go from 5b to 5, we use property 2 of the exponential distribution. Thus we prove only 5b here.

Assume that n units are put on test at time 0. Potential lifetimes of these are T_1, \dots, T_n , and hence $T_{(1)} = \min(T_1, \dots, T_n)$, so by property 4 above we already have $T_{(1)} \sim \text{expon}(n\lambda)$.

After time $T_{(1)}$ there are $n - 1$ unfailed units. At time $s = T_{(1)}$ each of these has by property 1 a remaining lifetime which is $\text{expon}(\lambda)$. It follows from this that we from time $T_{(1)}$ and onwards have the same situation as at time 0, only that there are now $n - 1$ instead of n units on test. Therefore the time to next failure, $T_{(2)} - T_{(1)}$, is distributed as the minimum of $n - 1$ $\text{expon}(\lambda)$ variables and hence is $\text{expon}((n - 1)\lambda)$. That $T_{(2)} - T_{(1)}$ is independent of $T_{(1)}$ follows from property 1 which says that, for the exponential distribution, the distribution of the remaining lifetime is the same whatever be the age of the item.

This reasoning can be continued at time $T_{(2)}$ in an obvious fashion, and we finish by concluding that $T_{(n)} - T_{(n-1)}$ is $\text{expon}(\lambda)$.